Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/700,085	CHEN ET AL.
Examiner	Art Unit
Cuong Q. Nguyen	2811

SEARCHED			
Class	Subclass	Date	Examiner
257	347-353	2-15-05	ar V
	347-353	2-15-05	<i>y</i>

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST+ EPIFTPU	2-1505	a